

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
		Examiner Long Pham	Art Unit 2814	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0050626	05-2002	Onuma et al.	257/531
*	B US-2004/0185183	09-2004	Srinivasan et al.	427/578
*	C US-2001/0053672	12-2001	Masaki, Toshiyuki	455/90
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	2001-308273	11-2001	Japan	Maeda	
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.